

## EPC2015C – Enhancement Mode Power Transistor

 $V_{DS}$ , 40 V $R_{DS(on)}$ , 4 m $\Omega$  $I_D$ , 53 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

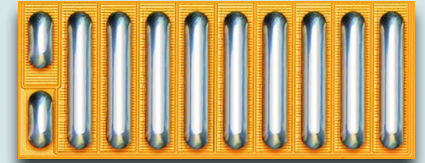
Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 6^\circ\text{C/W}$ )	53	A
	Pulsed (25°C, $T_{PULSE} = 300 \mu\text{s}$ )	235	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.8	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction to Board	1.7	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	54	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [http://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 500 \mu\text{A}$	40			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 32 \text{ V}$		200	400	$\mu\text{A}$
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	7	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		200	400	$\mu\text{A}$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 9 \text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 33 \text{ A}$		3.2	4	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.7		V

All measurements were done with substrate connected to source.



EPC2015C eGaN® FETs are supplied only in passivated die form with solder bars  
Die size: 4.1 mm x 1.6 mm

**Applications**

- High Frequency DC-DC Conversion
- Point-of-Load Converters
- Industrial Automation
- Synchronous Rectification
- Class-D Audio
- Low Inductance Motor Drives

**Benefits**

- Ultra High Efficiency
- Ultra Low Switching and Conduction Losses
- Zero  $Q_{RR}$
- Ultra Small Footprint



Dynamic Characteristics ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		980	1180	pF
$C_{RSS}$	Reverse Transfer Capacitance			18		
$C_{OSS}$	Output Capacitance			710	1070	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }20\text{ V}, V_{GS} = 0\text{ V}$		870		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			940		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 33\text{ A}$		8.7	11.2	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 20\text{ V}, I_D = 33\text{ A}$		2.7		
$Q_{GD}$	Gate-to-Drain Charge			1.2		
$Q_{G(TH)}$	Gate Charge at Threshold			1.9		
$Q_{OSS}$	Output Charge	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		19	29	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at 25°C

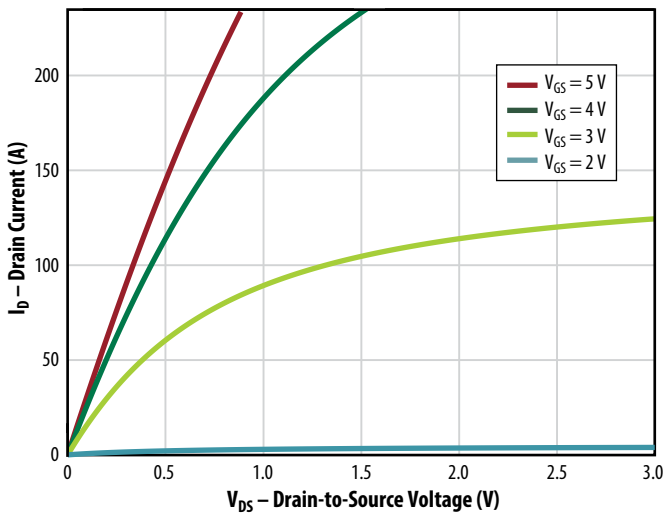


Figure 2: Transfer Characteristics

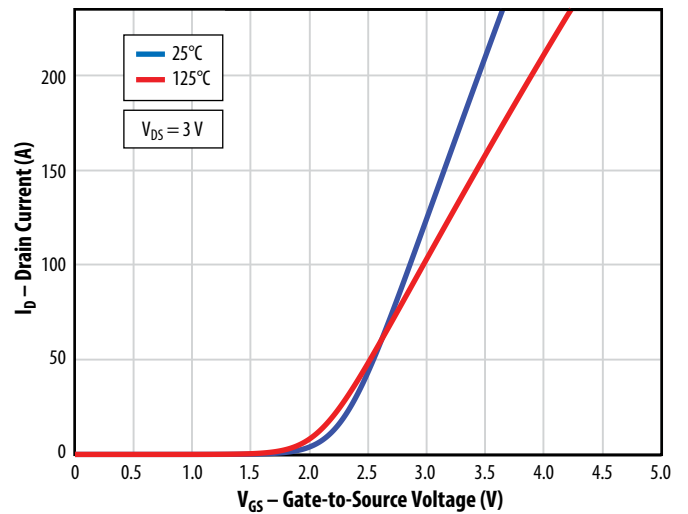


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

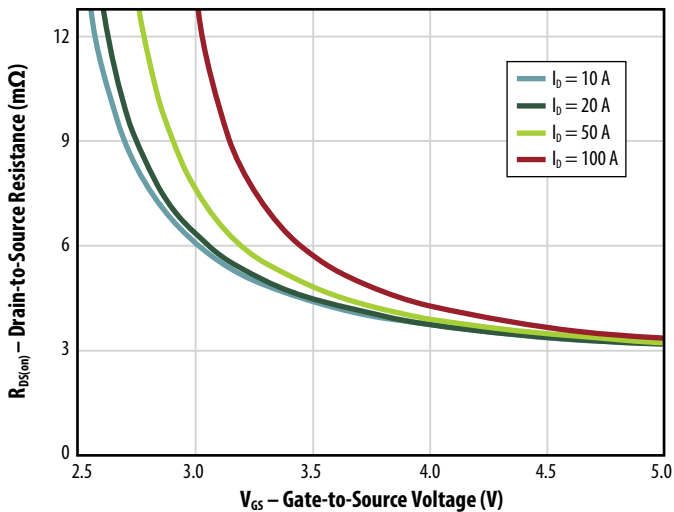


Figure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

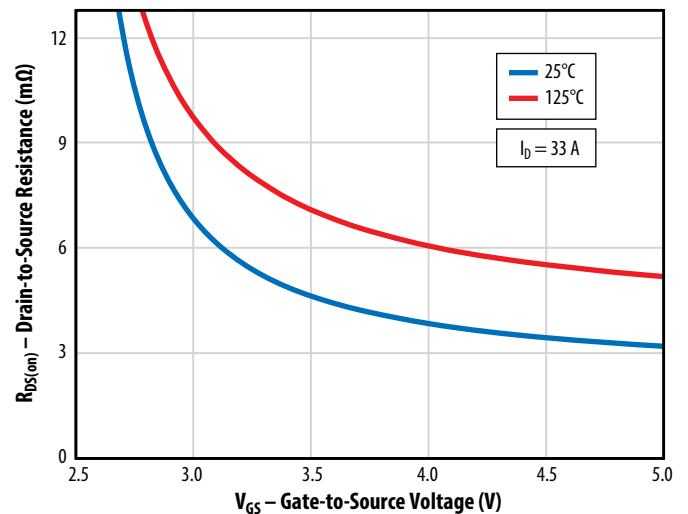


Figure 5a: Capacitance (Linear Scale)

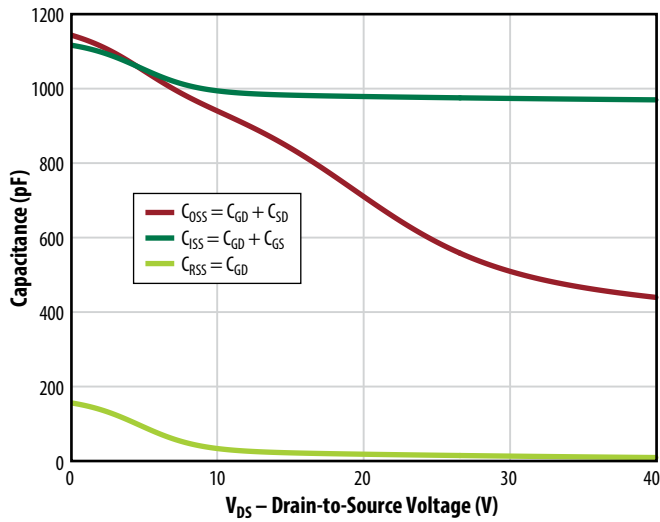


Figure 5b: Capacitance (Log Scale)

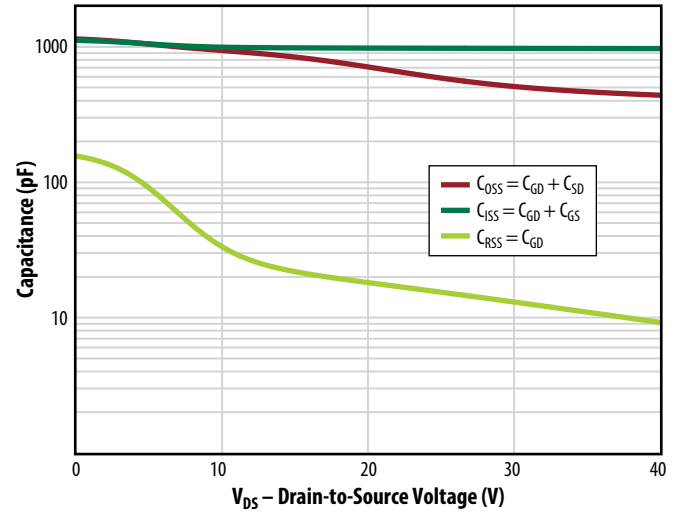


Figure 6: Gate Charge

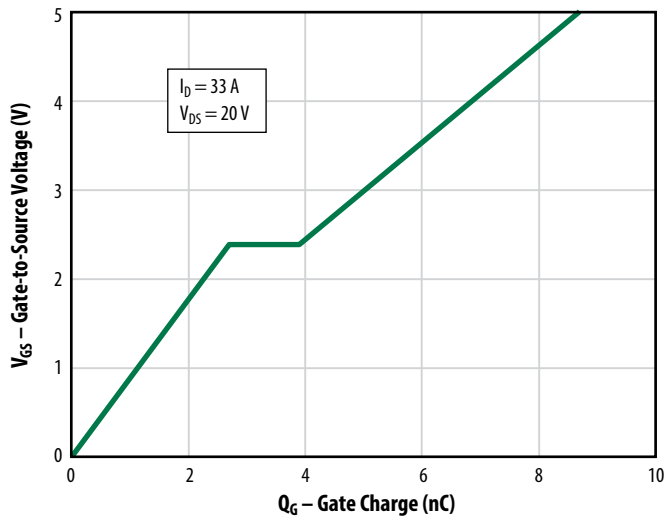


Figure 7: Reverse Drain-Source Characteristics

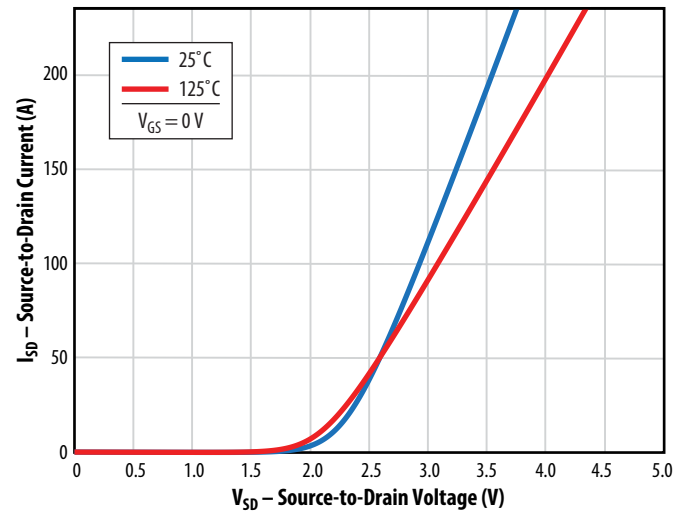


Figure 8: Normalized On-State Resistance vs. Temperature

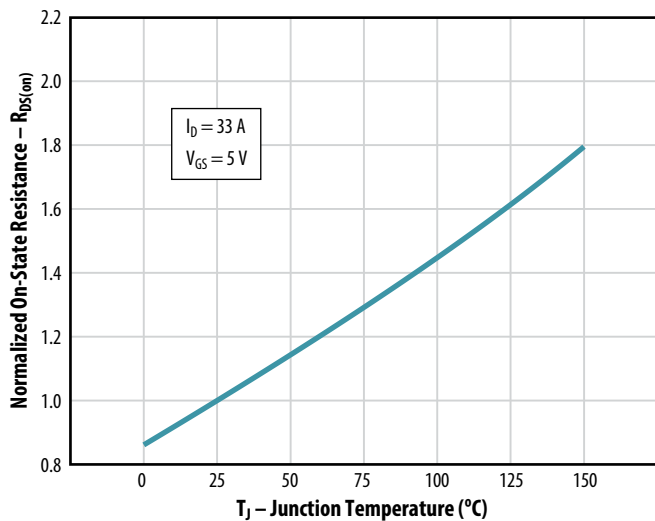
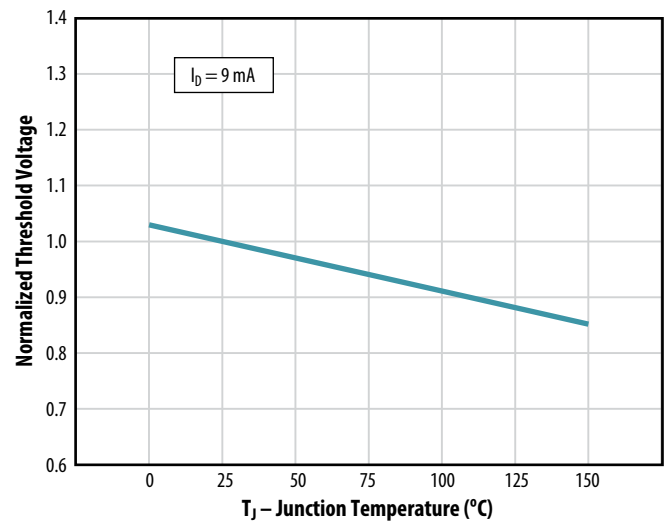


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Gate Leakage Current

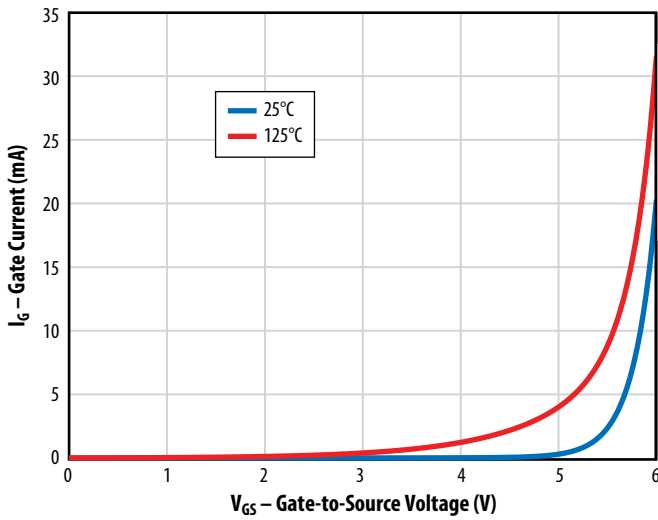


Figure 11: Safe Operating Area

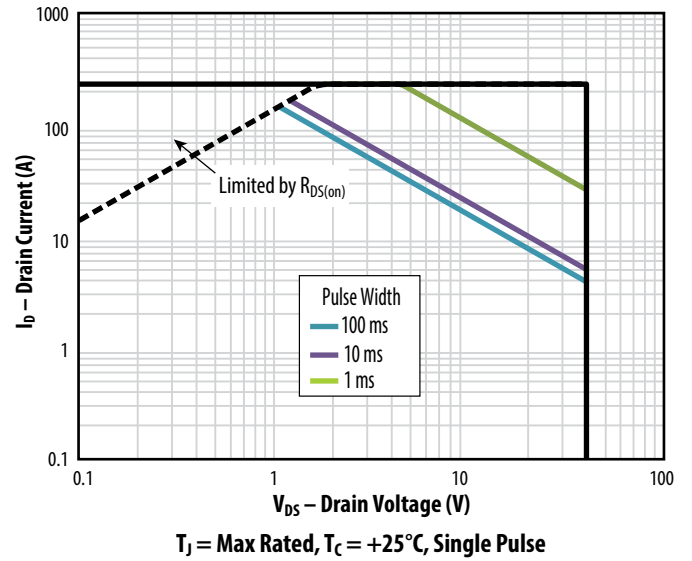
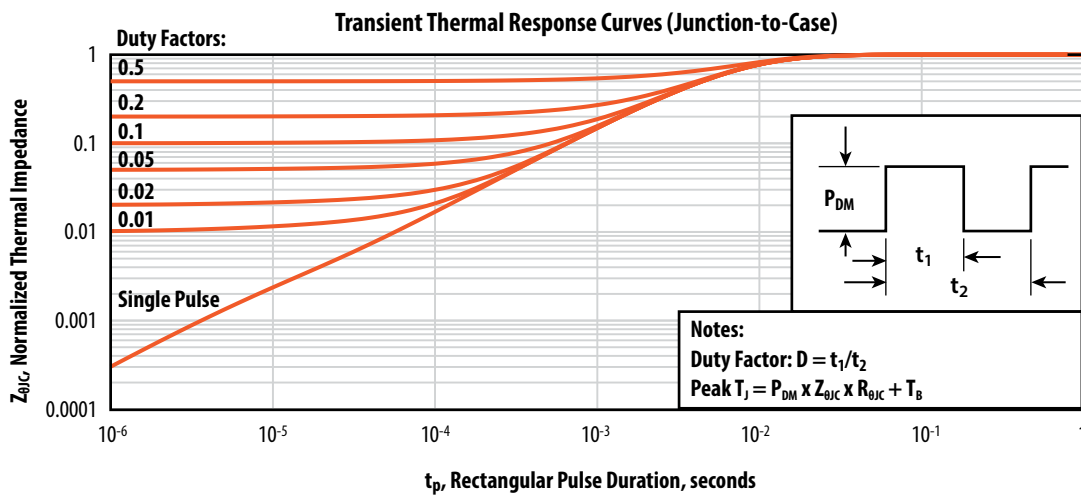
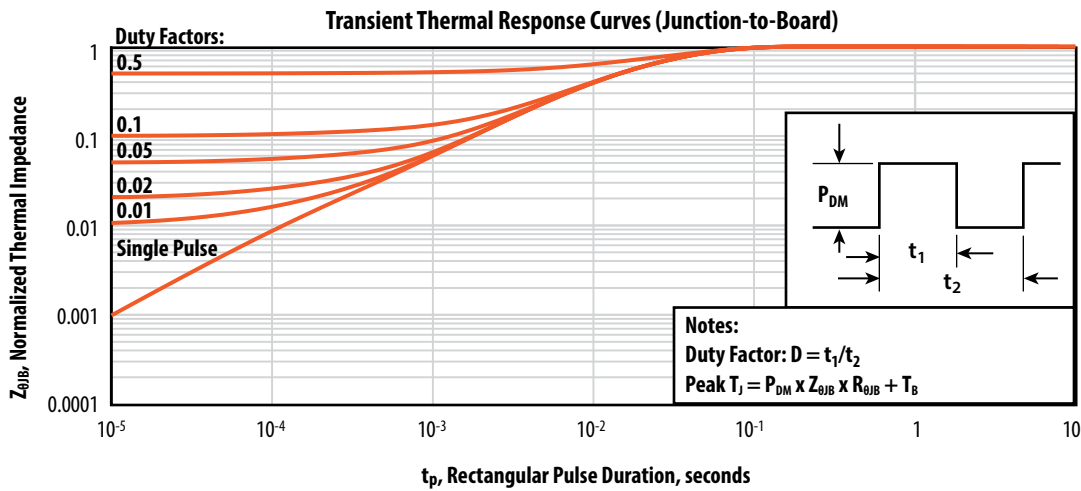
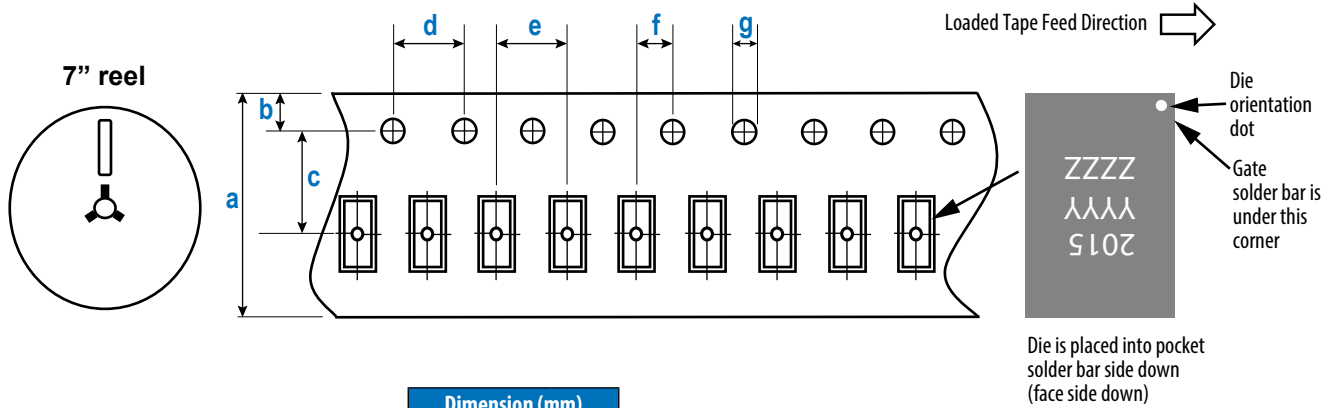


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

4 mm pitch, 12 mm wide tape on 7" reel

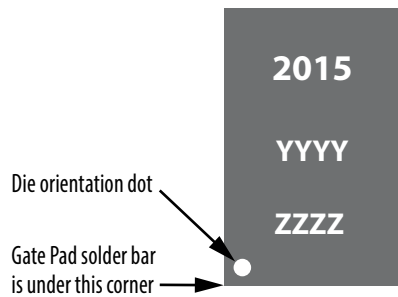


EPC2015 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
<b>a</b>	12.00	11.90	12.30
<b>b</b>	1.75	1.65	1.85
<b>c</b> (Note 2)	5.50	5.45	5.55
<b>d</b>	4.00	3.90	4.10
<b>e</b>	4.00	3.90	4.10
<b>f</b> (Note 2)	2.00	1.95	2.05
<b>g</b>	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

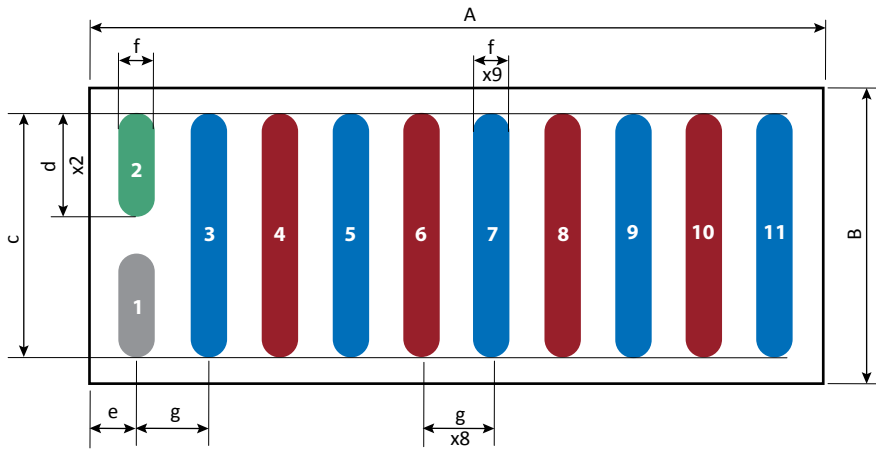
**DIE MARKINGS**



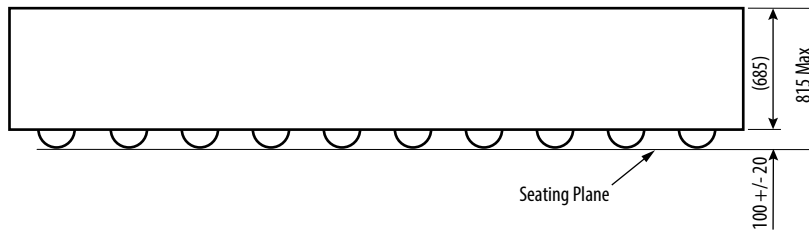
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_ Date Code Marking Line 2	Lot_ Date Code Marking Line 3
EPC2015C	2015	YYYY	ZZZZ

**DIE OUTLINE**

Solder Bar View



Side View



DIM	MICROMETERS		
	MIN	Nominal	MAX
A	4075	4105	4135
B	1602	1635	1662
c	1379	1382	1385
d	577	580	583
e	235	250	265
f	195	200	205
g	400	400	400

Pad no. 1 is Gate;

Pads no. 3, 5, 7, 9, 11 are Drain;

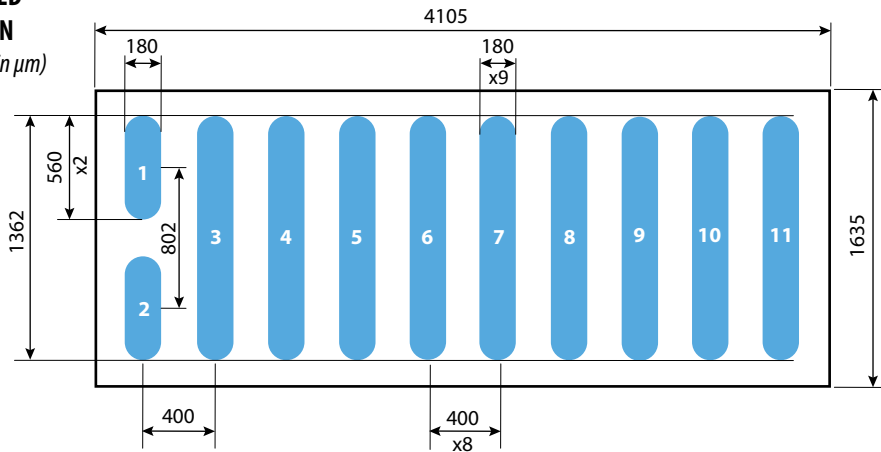
Pads no. 4, 6, 8, 10 are Source;

Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**

(measurements in  $\mu\text{m}$ )



The land pattern is solder mask defined.

Pad no. 1 is Gate;

Pads no. 3, 5, 7, 9, 11 are Drain;

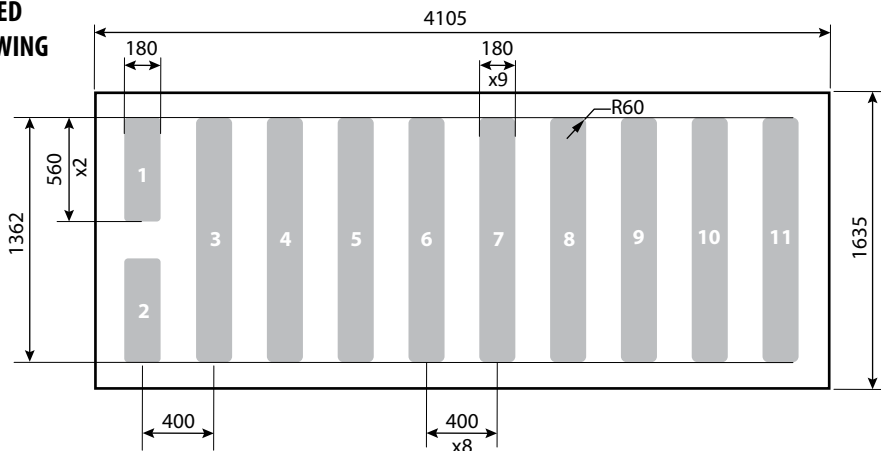
Pads no. 4, 6, 8, 10 are Source;

Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**

(units in  $\mu\text{m}$ )



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

eGaN® is a registered trademark of Efficient Power Conversion Corporation.

EPC Patent Listing: [epc-co.com/epc/AboutEPC/Patents.aspx](http://epc-co.com/epc/AboutEPC/Patents.aspx)

Information subject to change without notice.

Revised April, 2021